

# 1-Mbit (128 K × 8) Static RAM

#### **Features**

- Pin- and function-compatible with CY7C1019B
- High speed

  □ t<sub>AA</sub> = 10 ns
- Low active power
  □ I<sub>CC</sub> = 80 mA @ 10 ns
- Low CMOS standby power
  □ I<sub>SB2</sub> = 3 mA
- 2.0 V Data retention
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Center power/ground pinout
- Easy memory expansion with  $\overline{\text{CE}}$  and  $\overline{\text{OE}}$  options
- Functionally equivalent to CY7C1019B
- Available in Pb-free 32-pin 400-Mil wide Molded SOJ and 32-pin TSOP II packages

### **Functional Description**

The CY7C1019D <sup>[1]</sup> is a high-performance CMOS static RAM organized as 131,072 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable (CE), an active LOW Output Enable (OE), and tri-state drivers. This device has an automatic power-down feature that significantly reduces power consumption when deselected. The eight input and output pins ( $IO_0$  through  $IO_7$ ) are placed in a high-impedance state when:

- Deselected (CE HIGH)
- Outputs are disabled (OE HIGH)
- When the write operation is active ( $\overline{CE}$  LOW, and  $\overline{WE}$  LOW).

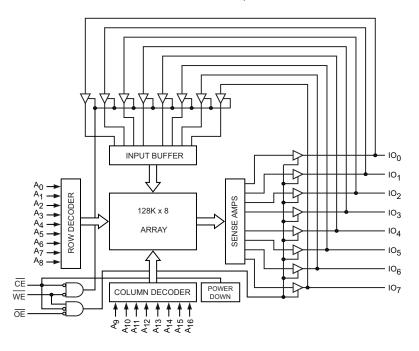
Write to the device by taking Chip Enable  $(\overline{CE})$  and Write Enable  $(\overline{WE})$  inputs LOW. Data on the eight IO pins  $(IO_0$  through  $IO_7)$  is then written into the location specified on the address pins  $(A_0$  through  $A_{16})$ .

Read from the device by taking Chip Enable  $(\overline{CE})$  and Output Enable  $(\overline{OE})$  LOW while forcing Write Enable  $(\overline{WE})$  HIGH. Under these conditions, the contents of the memory location specified by the address pins appears on the IO pins.

The CY7C1019D device is suitable for interfacing with processors that have TTL I/P levels. It is not suitable for processors that require CMOS I/P levels. Please see Electrical Characteristics on page 4 for more details and suggested alternatives.

For a complete list of related documentation, click here.

# **Logic Block Diagram**



#### Note

1. For guidelines on SRAM system design, please refer to the 'System Design Guidelines' Cypress application note, available on the internet at www.cypress.com.

Revised November 26, 2014



# Contents

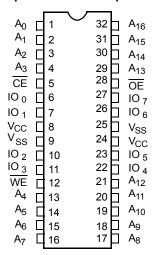
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# **Pin Configuration**

Figure 1. 32-pin SOJ / TSOP II pinout (Top View)



# **Selection Guide**

| Description               | -10 (Industrial) | Unit |
|---------------------------|------------------|------|
| Maximum Access Time       | 10               | ns   |
| Maximum Operating Current | 80               | mA   |
| Maximum Standby Current   | 3                | mA   |



### **Maximum Ratings**

Exceeding the maximum ratings may impair the useful life of the device. These user guidelines are not tested. Storage Temperature ......-65 °C to +150 °C Ambient Temperature with Power Applied ......–55 °C to +125 °C Supply Voltage on V  $_{CC}$  to Relative GND  $^{[2]}$  .....–0.5 V to +6.0 V 

| DC Input Voltage [2]                                    | 0.5 V to V <sub>CC</sub> + 0.5 V |
|---|----------------------------------|
| Current into Outputs (LOW)                              | 20 mA                            |
| Static Discharge Voltage (per MIL-STD-883, Method 3015) | > 2001 V                         |
| Latch-up Current  | > 200 mA                         |

### **Operating Range**

| Range      | Ambient<br>Temperature | V <sub>CC</sub> | Speed |
|------------|------------------------|-----------------|-------|
| Industrial | –40 °C to +85 °C       | 5 V $\pm$ 0.5 V | 10 ns |

#### **Electrical Characteristics**

Over the Operating Range

| Downston         | Decemention                                      | Took Conditions   |                          | -10 (Inc   | dustrial)             | I I m ! 4 |
|------------------|--|---|--------------------------|------------|-----------------------|-----------|
| Parameter        | Description                                      | lest Conditions   | Test Conditions          |            | Max                   | Unit      |
| V <sub>OH</sub>  | Output HIGH Voltage                              | /oltage I <sub>OH</sub> = -4.0 mA   |                          | 2.4        | _                     | V         |
|                  |  | $I_{OH} = -0.1 \text{ mA}$  |                          | _          | 3.4 <sup>[3]</sup>    |           |
| V <sub>OL</sub>  | Output LOW Voltage                               | I <sub>OL</sub> = 8.0 mA  |                          | _          | 0.4                   | V         |
| V <sub>IH</sub>  | Input HIGH Voltage                               |   |                          | 2.2        | V <sub>CC</sub> + 0.5 | V         |
| V <sub>IL</sub>  | Input LOW Voltage [2]                            |   |                          |            |                       | V         |
| I <sub>IX</sub>  | Input Leakage Current                            | $GND \le V_I \le V_{CC}$  | $GND \le V_1 \le V_{CC}$ |            | +1                    | μΑ        |
| I <sub>OZ</sub>  | Output Leakage Current                           | $GND \le V_I \le V_{CC}$ , Output Disabled  |                          | <b>–</b> 1 | +1                    | μΑ        |
| I <sub>CC</sub>  | V <sub>CC</sub> Operating Supply Current         | $V_{CC}$ = Max, $I_{OUT}$ = 0 mA,<br>f = $f_{max}$ = 1/ $t_{RC}$  | 100 MHz                  | _          | 80                    | mA        |
|                  |  |   | 83 MHz                   | _          | 72                    | mA        |
|                  |  |   | 66 MHz                   | _          | 58                    | mA        |
|                  |  |   | 40 MHz                   | _          | 37                    | mA        |
| I <sub>SB1</sub> | Automatic CE Power-Down<br>Current – TTL Inputs  | $Max V_{CC}, \overline{CE} \ge V_{IH}, V_{IN} \ge V_{IH} \text{ or } V_{IN} \le V_{IL}, f = f_{max}$  |                          | _          | 10                    | mA        |
| I <sub>SB2</sub> | Automatic CE Power-Down<br>Current – CMOS Inputs | $\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \text{ or V}_{\text{IN}} \leq 0.3 \text{ V}, \text{ f} = \end{aligned}$ | 0                        | -          | 3                     | mA        |

#### Note

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V<sub>IL</sub> (min) = -2.0 V and V<sub>IH</sub>(max) = V<sub>CC</sub> + 1 V for pulse durations of less than 5 ns.
 Please note that the maximum V<sub>OH</sub> limit doesnot exceed minimum CMOS VIH of 3.5V. If you are interfacing this SRAM with 5 V legacy processors that require a minimum V<sub>IH</sub> of 3.5 V, please refer to Application Note AN6081 for technical details and options you may consider.



# Capacitance

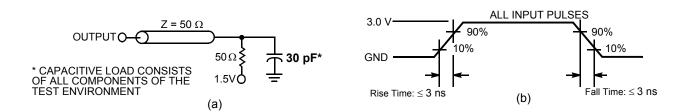
| Parameter [4]    | Description        | Test Conditions   | Max | Unit |
|------------------|--------------------|---|-----|------|
| C <sub>IN</sub>  | Input capacitance  | $T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz},  V_{CC} = 5.0 \text{V}$ | 6   | pF   |
| C <sub>OUT</sub> | Output capacitance |   | 8   | pF   |

# **Thermal Resistance**

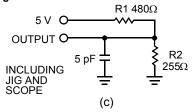
| Parameter [4]     | Description                           | Test Conditions   | 400-Mil Wide<br>SOJ | TSOP II | Unit |
|-------------------|---------------------------------------|---|---------------------|---------|------|
| $\Theta_{JA}$     |                                       | Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit board | 56.29               | 62.22   | °C/W |
| $\Theta_{\sf JC}$ | Thermal resistance (junction to case) |   | 38.14               | 21.43   | °C/W |

### **AC Test Loads and Waveforms**

Figure 2. AC Test Loads and Waveforms [5]



#### High Z characteristics:



#### Notes

- 4. Tested initially and after any design or process changes that may affect these parameters.
- 5. AC characteristics (except High Z) are tested using the load conditions shown in Figure 2 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 2 (c).

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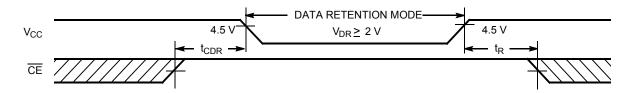
# **Data Retention Characteristics**

Over the Operating Range

| Parameter                       | Description                          | Conditions   | Min             | Max | Unit |
|---------------------------------|--------------------------------------|--|-----------------|-----|------|
| $V_{DR}$                        | V <sub>CC</sub> for Data Retention   |  | 2.0             | -   | V    |
| I <sub>CCDR</sub>               | Data Retention Current               | $V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V},$<br>$V_{IN} \ge V_{CC} - 0.3 \text{ V or } V_{IN} \le 0.3 \text{ V}$ | _               | 3   | mA   |
| t <sub>CDR</sub> <sup>[6]</sup> | Chip Deselect to Data Retention Time |  | 0               | _   | ns   |
| t <sub>R</sub> <sup>[7]</sup>   | Operation Recovery Time              |  | t <sub>RC</sub> | _   | ns   |

### **Data Retention Waveform**

Figure 3. Data Retention Waveform



 <sup>6.</sup> Tested initially and after any design or process changes that may affect these parameters.
 7. Full device operation requires linear V<sub>CC</sub> ramp from V<sub>DR</sub> to V<sub>CC(min)</sub> ≥ 50 μs or stable at V<sub>CC(min)</sub> ≥ 50 μs.



# **Switching Characteristics**

Over the Operating Range

| Parameter [8]          | Description                                   | -10 (Inc | lustrial) | 11:4 |
|------------------------|---|----------|-----------|------|
| Parameter [9]          | Description                                   | Min      | Max       | Unit |
| Read Cycle             |   |          |           |      |
| t <sub>power</sub> [9] | V <sub>CC</sub> (typical) to the first access | 100      | _         | μS   |
| t <sub>RC</sub>        | Read Cycle Time                               | 10       | _         | ns   |
| t <sub>AA</sub>        | Address to Data Valid                         | -        | 10        | ns   |
| t <sub>OHA</sub>       | Data Hold from Address Change                 | 3        | _         | ns   |
| t <sub>ACE</sub>       | CE LOW to Data Valid                          | -        | 10        | ns   |
| t <sub>DOE</sub>       | OE LOW to Data Valid                          | -        | 5         | ns   |
| t <sub>LZOE</sub>      | OE LOW to Low Z                               | 0        | _         | ns   |
| t <sub>HZOE</sub>      | OE HIGH to High Z [10, 11]                    | -        | 5         | ns   |
| t <sub>LZCE</sub>      | CE LOW to Low Z [11]                          | 3        | _         | ns   |
| t <sub>HZCE</sub>      | CE HIGH to High Z [10, 11]                    | _        | 5         | ns   |
| t <sub>PU</sub> [12]   | CE LOW to Power-Up                            | 0        | _         | ns   |
| t <sub>PD</sub> [12]   | CE HIGH to Power-Down                         | -        | 10        | ns   |
| Write Cycle [13        | , 14]   | ·        |           |      |
| t <sub>WC</sub>        | Write Cycle Time                              | 10       | _         | ns   |
| t <sub>SCE</sub>       | CE LOW to Write End                           | 7        | _         | ns   |
| t <sub>AW</sub>        | Address Set-Up to Write End                   | 7        | _         | ns   |
| t <sub>HA</sub>        | Address Hold from Write End                   | 0        | _         | ns   |
| t <sub>SA</sub>        | Address Set-Up to Write Start                 | 0        | _         | ns   |
| t <sub>PWE</sub>       | WE Pulse Width                                | 7        | _         | ns   |
| t <sub>SD</sub>        | Data Set-Up to Write End                      | 6        | _         | ns   |
| t <sub>HD</sub>        | Data Hold from Write End                      | 0        | _         | ns   |
| t <sub>LZWE</sub>      | WE HIGH to Low Z [11]                         | 3        | _         | ns   |
| t <sub>HZWE</sub>      | WE LOW to High Z [10, 11]                     | _        | 5         | ns   |

- 8. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I<sub>QL</sub>/I<sub>QH</sub> and 30-pF load capacitance.
- 10. t<sub>HZOE</sub>, t<sub>HZOE</sub>, and t<sub>HZWE</sub> are specified with a load capacitance of 5 pF as in (c) of Figure 2 on page 5. Transition is measured when the outputs enter a high impedance state.

  11. At any given temperature and voltage condition, t<sub>HZCE</sub> is less than t<sub>LZOE</sub>, t<sub>HZOE</sub> is less than t<sub>LZOE</sub>, and t<sub>HZWE</sub> is less than t<sub>LZOE</sub> for any given device.

  12. This parameter is guaranteed by design and is not tested.

- The internal write time of the memory is defined by the overlap of CE LOW and WE LOW. CE and WE must be LOW to initiate a write, and the transition of any of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.
   The minimum write cycle time for Write Cycle no. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.



# **Switching Waveforms**

Figure 4. Read Cycle No. 1 (Address Transition Controlled) [15, 16]

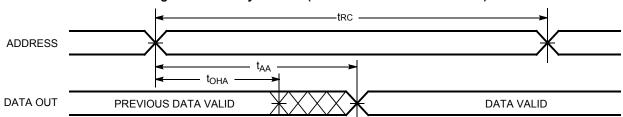
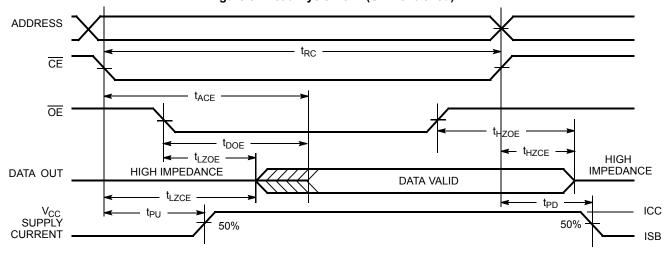


Figure 5. Read Cycle No. 2 (OE Controlled) [16, 17]



<sup>15. &</sup>lt;u>Device</u> is continuously selected. <u>OE</u>, <u>CE</u> = V<sub>IL</sub>.

16. <u>WE</u> is HIGH for Read cycle.

17. Address valid prior to or coincident with <u>CE</u> transition LOW.



# Switching Waveforms (continued)

Figure 6. Write Cycle No. 1 (CE Controlled) [18, 19]

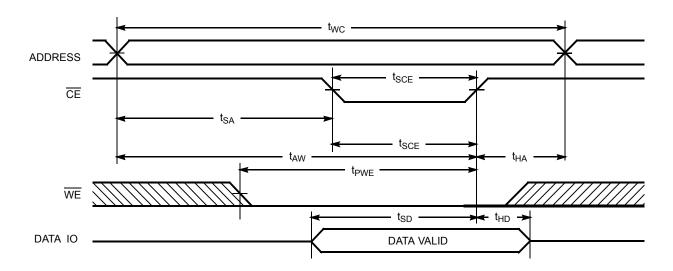
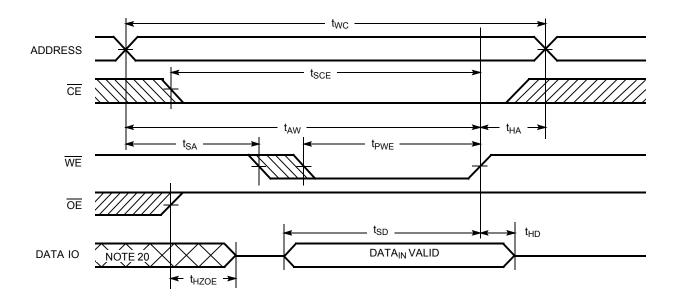


Figure 7. Write Cycle No. 2 (WE Controlled, OE HIGH During Write) [18, 19]



<sup>18.</sup> Data IO is high impedance if  $\overline{OE} = \underline{V_{IH}}$ .

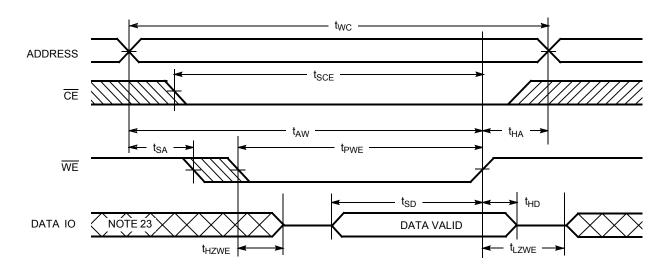
19. If  $\overline{CE}$  goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

20. During this period the IOs are in the output state and input signals should not be applied.



# Switching Waveforms (continued)

Figure 8. Write Cycle No. 3 ( $\overline{\text{WE}}$  Controlled,  $\overline{\text{OE}}$  LOW) [21, 22]



<sup>21.</sup> The minimum write cycle time for <u>Write</u> Cycle no. 3 (WE controlled, OE LOW) is the sum of t<sub>HZWE</sub> and t<sub>SD</sub>.

22. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high-impedance state.

23. During this period the IOs are in the output state and input signals should not be applied.



### **Truth Table**

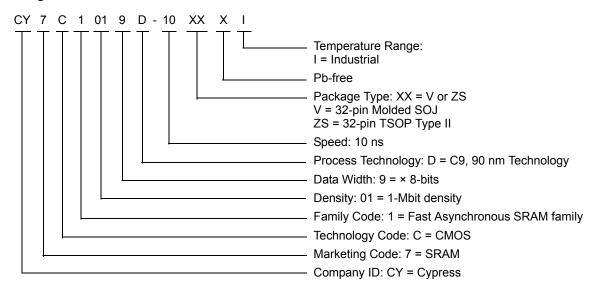
| CE | OE | WE | IO <sub>0</sub> -IO <sub>7</sub> | Mode                       | Power                      |
|----|----|----|----------------------------------|----------------------------|----------------------------|
| Н  | Х  | Х  | High Z                           | Power-Down                 | Standby (I <sub>SB</sub> ) |
| L  | L  | Н  | Data Out                         | Read                       | Active (I <sub>CC</sub> )  |
| L  | Х  | L  | Data In                          | Write                      | Active (I <sub>CC</sub> )  |
| L  | Н  | Н  | High Z                           | Selected, Outputs Disabled | Active (I <sub>CC</sub> )  |

# **Ordering Information**

| Speed (ns) | Ordering Code    | Package<br>Diagram | Package Type                  | Operating Range |
|------------|------------------|--------------------|-------------------------------|-----------------|
| 10         | CY7C1019D-10VXI  | 51-85033           | 32-pin SOJ (400 Mils) Pb-free | Industrial      |
|            | CY7C1019D-10ZSXI | 51-85095           | 32-pin TSOP (Type II) Pb-free |                 |

Please contact your local Cypress sales representative for availability of these parts.

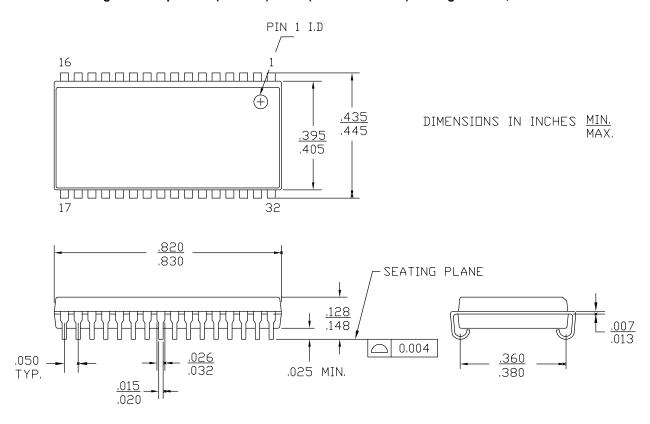
#### **Ordering Code Definitions**





# **Package Diagrams**

Figure 9. 32-pin SOJ (400 Mils) V32.4 (Molded SOJ V33) Package Outline, 51-85033

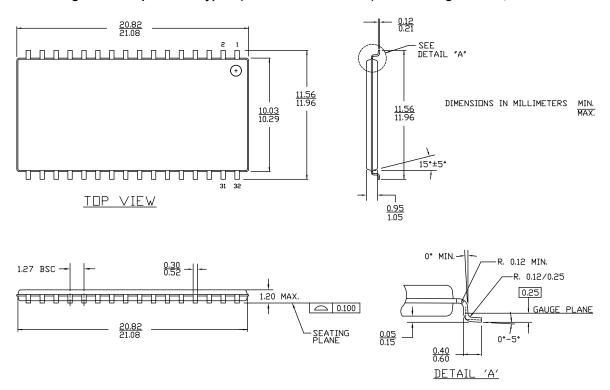


51-85033 \*E



# Package Diagrams (continued)

Figure 10. 32-pin TSOP Type II (20.95 × 11.76 × 1.0 mm) ZS32 Package Outline, 51-85095



51-85095 \*B



# Acronyms

| Acronym | Description                             |  |  |
|---------|---|--|--|
| CE      | Chip Enable                             |  |  |
| CMOS    | Complementary Metal Oxide Semiconductor |  |  |
| I/O     | Input/Output                            |  |  |
| OE      | Output Enable                           |  |  |
| SOJ     | Small Outline J-lead                    |  |  |
| SRAM    | Static Random Access Memory             |  |  |
| TSOP    | Thin Small Outline Package              |  |  |
| TTL     | Transistor-Transistor Logic             |  |  |
| WE      | Write Enable                            |  |  |

# **Document Conventions**

### **Units of Measure**

| Symbol | Unit of Measure |  |  |  |
|--------|-----------------|--|--|--|
| °C     | degree Celsius  |  |  |  |
| MHz    | megahertz       |  |  |  |
| μΑ     | microampere     |  |  |  |
| μs     | microsecond     |  |  |  |
| mA     | milliampere     |  |  |  |
| ms     | millisecond     |  |  |  |
| mm     | millimeter      |  |  |  |
| ns     | nanosecond      |  |  |  |
| Ω      | ohm             |  |  |  |
| %      | percent         |  |  |  |
| pF     | picofarad       |  |  |  |
| V      | volt            |  |  |  |
| W      | watt            |  |  |  |



# **Document History Page**

| Document Title: CY7C1019D, 1-Mbit (128 K × 8) Static RAM<br>Document Number: 38-05464 |         |            |                    |  |  |  |
|---|---------|------------|--------------------|--|--|--|
| Rev.  | ECN No. | Issue Date | Orig. of<br>Change | Description of Change  |  |  |
| **  | 201560  | See ECN    | SWI                | Advance Information data sheet for C9 IPP  |  |  |
| *A  | 233715  | See ECN    | RKF                | DC parameters are modified as per EROS (Spec # 01-2165) Pb-free offering in the Ordering Information   |  |  |
| *B  | 262950  | See ECN    | RKF                | Added T <sub>power</sub> Spec in Switching Characteristics table Added Data Retention Characteristics table and waveforms Shaded Ordering Information  |  |  |
| *C  | 307598  | See ECN    | RKF                | Reduced Speed bins to -10 and -12 ns   |  |  |
| *D  | 520647  | See ECN    | VKN                | Converted from Preliminary to Final Removed Commercial Operating range Removed 12 ns speed bin Added I <sub>CC</sub> values for the frequencies 83MHz, 66MHz and 40MHz Updated Thermal Resistance table Updated Ordering Information Table Changed Overshoot spec from V <sub>CC</sub> +2V to V <sub>CC</sub> +1V in footnote #2   |  |  |
| *E  | 802877  | See ECN    | VKN                | Changed I <sub>CC</sub> spec from 60 mA to 80 mA for 100MHz, 55 mA to 72 mA for 83MHz, 45 mA to 58 mA for 66MHz, 30 mA to 37 mA for 40MHz  |  |  |
| *F  | 3110052 | 12/14/2010 | AJU                | Added Ordering Code Definitions. Updated Package Diagrams.   |  |  |
| *G  | 3245896 | 05/02/2011 | PRAS               | Updated Package Diagrams. Added Acronyms and Units of Measure. Updated in new template.  |  |  |
| *H  | 4038234 | 06/24/2013 | MEMJ               | Updated Functional Description. Updated Electrical Characteristics: Added one more Test Condition " $I_{OH}$ = $-0.1$ mA" for $V_{OH}$ parameter and added maximum value corresponding to that Test Condition. Added Note 3 and referred the same note in maximum value for $V_{OH}$ parameter corresponding to Test Condition " $I_{OH}$ = $-0.1$ mA". Updated in new template. |  |  |
| *   | 4385827 | 05/21/2014 | MEMJ               | Updated Package Diagrams: spec 51-85033 – Changed revision from *D to *E. Completing Sunset Review.  |  |  |
| *J  | 4579569 | 11/26/2014 | MEMJ               | Added related documentation hyperlink in page 1.   |  |  |



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